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(19) **United States**(12) **Patent Application Publication****Wu et al.**(10) **Pub. No.: US 2010/0315627 A1**(43) **Pub. Date: Dec. 16, 2010**(54) **APPARATUS AND METHOD FOR
ENHANCING THE ELECTROMAGNETIC
SIGNAL OF A SAMPLE**(76) Inventors: **Wen-Li Wu**, Gaithersburg, MD
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The present invention is an apparatus and method for enhancing the electromagnetic signal of a sample for ellipsometry which uses at least one auxiliary layer and at least one substrate layer.

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